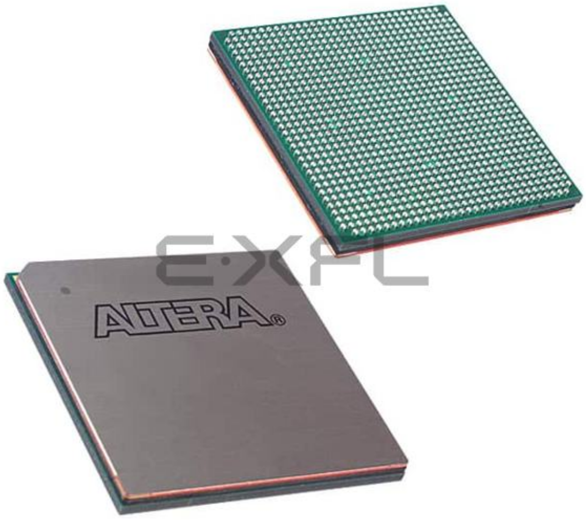
Intel - EP2S60F1020C3N Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	3022
Number of Logic Elements/Cells	60440
Total RAM Bits	2544192
Number of I/O	718
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1020-BBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2s60f1020c3n

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Section I. Stratix II Device Family Data Sheet

Chapter 1. Introduction

Chapter 2. Stratix II Architecture

1. Introduction

SII51001-4.2

Introduction

The Stratix® II FPGA family is based on a 1.2-V, 90-nm, all-layer copper SRAM process and features a new logic structure that maximizes performance, and enables device densities approaching 180,000 equivalent logic elements (LEs). Stratix II devices offer up to 9 Mbits of on-chip, TriMatrix™ memory for demanding, memory intensive applications and has up to 96 DSP blocks with up to 384 (18-bit × 18-bit) multipliers for efficient implementation of high performance filters and other DSP functions. Various high-speed external memory interfaces are supported, including double data rate (DDR) SDRAM and DDR2 SDRAM, RLDRAM II, quad data rate (QDR) II SRAM, and single data rate (SDR) SDRAM. Stratix II devices support various I/O standards along with support for 1-gigabit per second (Gbps) source synchronous signaling with DPA circuitry. Stratix II devices offer a complete clock management solution with internal clock frequency of up to 550 MHz and up to 12 phase-locked loops (PLLs). Stratix II devices are also the industry's first FPGAs with the ability to decrypt a configuration bitstream using the Advanced Encryption Standard (AES) algorithm to protect designs.

Features

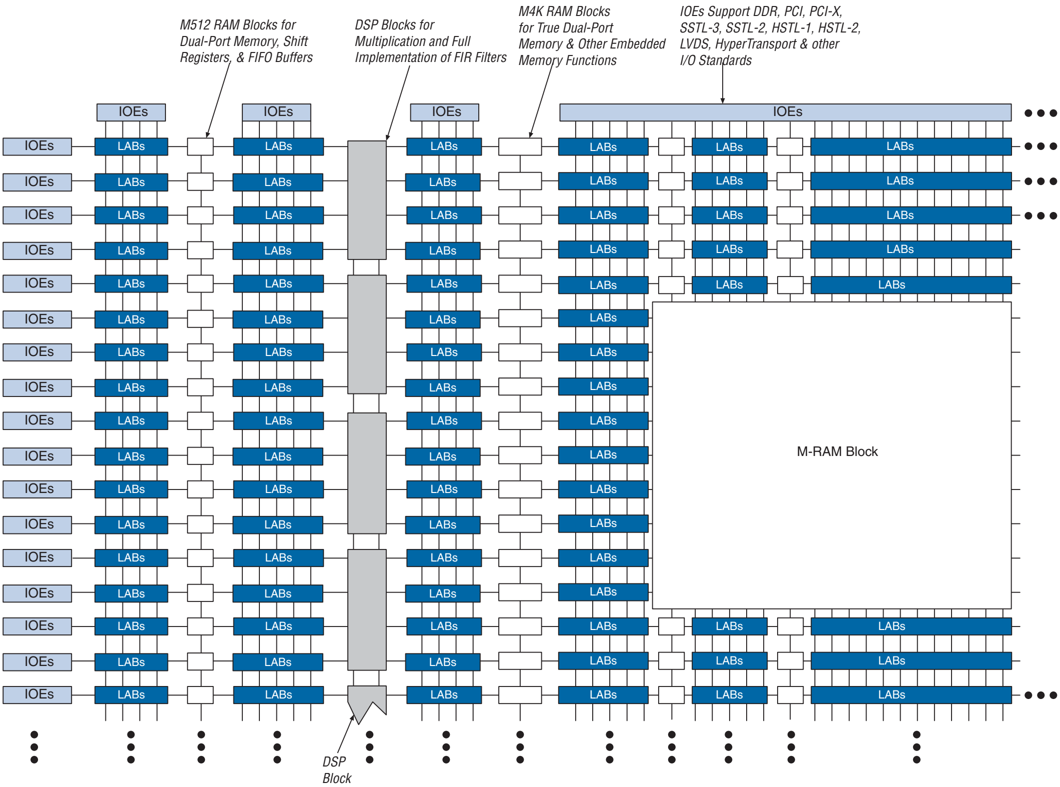
The Stratix II family offers the following features:

- 15,600 to 179,400 equivalent LEs; see Table 1–1
- New and innovative adaptive logic module (ALM), the basic building block of the Stratix II architecture, maximizes performance and resource usage efficiency
- Up to 9,383,040 RAM bits (1,172,880 bytes) available without reducing logic resources
- TriMatrix memory consisting of three RAM block sizes to implement true dual-port memory and first-in first-out (FIFO) buffers
- High-speed DSP blocks provide dedicated implementation of multipliers (at up to 450 MHz), multiply-accumulate functions, and finite impulse response (FIR) filters
- Up to 16 global clocks with 24 clocking resources per device region
- Clock control blocks support dynamic clock network enable/disable, which allows clock networks to power down to reduce power consumption in user mode
- Up to 12 PLLs (four enhanced PLLs and eight fast PLLs) per device provide spread spectrum, programmable bandwidth, clock switch-over, real-time PLL reconfiguration, and advanced multiplication and phase shifting

Each Stratix II device I/O pin is fed by an I/O element (IOE) located at the end of LAB rows and columns around the periphery of the device. I/O pins support numerous single-ended and differential I/O standards. Each IOE contains a bidirectional I/O buffer and six registers for registering input, output, and output-enable signals. When used with dedicated clocks, these registers provide exceptional performance and interface support with external memory devices such as DDR and DDR2 SDRAM, RLDRAM II, and QDR II SRAM devices. High-speed serial interface channels with dynamic phase alignment (DPA) support data transfer at up to 1 Gbps using LVDS or HyperTransport™ technology I/O standards.

Figure 2–1 shows an overview of the Stratix II device.

Figure 2–1. Stratix II Block Diagram



Clear & Preset Logic Control

LAB-wide signals control the logic for the register's clear and load/preset signals. The ALM directly supports an asynchronous clear and preset function. The register preset is achieved through the asynchronous load of a logic high. The direct asynchronous preset does not require a NOT-gate push-back technique. Stratix II devices support simultaneous asynchronous load/preset, and clear signals. An asynchronous clear signal takes precedence if both signals are asserted simultaneously. Each LAB supports up to two clears and one load/preset signal.

In addition to the clear and load/preset ports, Stratix II devices provide a device-wide reset pin (`DEV_CLRn`) that resets all registers in the device. An option set before compilation in the Quartus II software controls this pin. This device-wide reset overrides all other control signals.

MultiTrack Interconnect

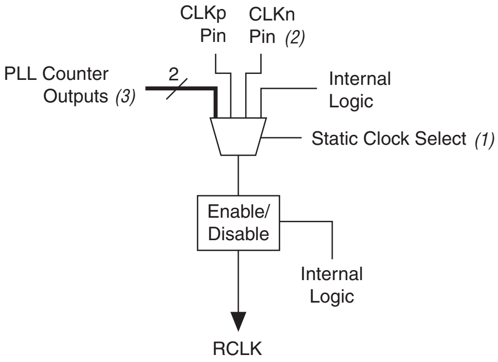
In the Stratix II architecture, connections between ALMs, TriMatrix memory, DSP blocks, and device I/O pins are provided by the MultiTrack interconnect structure with DirectDrive™ technology. The MultiTrack interconnect consists of continuous, performance-optimized routing lines of different lengths and speeds used for inter- and intra-design block connectivity. The Quartus II Compiler automatically places critical design paths on faster interconnects to improve design performance.

DirectDrive technology is a deterministic routing technology that ensures identical routing resource usage for any function regardless of placement in the device. The MultiTrack interconnect and DirectDrive technology simplify the integration stage of block-based designing by eliminating the re-optimization cycles that typically follow design changes and additions.

The MultiTrack interconnect consists of row and column interconnects that span fixed distances. A routing structure with fixed length resources for all devices allows predictable and repeatable performance when migrating through different device densities. Dedicated row interconnects route signals to and from LABs, DSP blocks, and TriMatrix memory in the same row. These row resources include:

- Direct link interconnects between LABs and adjacent blocks
- R4 interconnects traversing four blocks to the right or left
- R24 row interconnects for high-speed access across the length of the device

Figure 2–38. Regional Clock Control Blocks



Notes to Figure 2–38:

(1) These clock select signals can only be set through a configuration file (**.sof** or **.pof**) and cannot be dynamically controlled during user mode operation.

(2) Only the `CLKn` pins on the top and bottom of the device feed to regional clock select blocks.The clock outputs from corner PLLs cannot be dynamically selected through the global clock control block.

(3) The clock outputs from corner PLLs cannot be dynamically selected through the global clock control block.

Figure 2–43 shows the global and regional clocking from enhanced PLL outputs and top and bottom `CLK` pins. The connections to the global and regional clocks from the top clock pins and enhanced PLL outputs is shown in Table 2–11. The connections to the clocks from the bottom clock pins is shown in Table 2–12.

Table 2–11. Global & Regional Clock Connections from Top Clock Pins & Enhanced PLL Outputs (Part 2 of 2)

Top Side Global & Regional Clock Network Connectivity	DLLCLK	CLK12	CLK13	CLK14	CLK15	RCLK24	RCLK25	RCLK26	RCLK27	RCLK28	RCLK29	RCLK30	RCLK31
c4	✓					✓		✓		✓		✓	
c5	✓						✓		✓		✓		✓
Enhanced PLL 11 outputs													
c0		✓	✓			✓				✓			
c1		✓	✓				✓				✓		
c2				✓	✓			✓				✓	
c3				✓	✓				✓				✓
c4						✓		✓		✓		✓	
c5							✓		✓		✓		✓

Table 2–12. Global & Regional Clock Connections from Bottom Clock Pins & Enhanced PLL Outputs (Part 1 of 2)

Bottom Side Global & Regional Clock Network Connectivity	DLLCLK	CLK4	CLK5	CLK6	CLK7	RCLK8	RCLK9	RCLK10	RCLK11	RCLK12	RCLK13	RCLK14	RCLK15
Clock pins													
CLK4p	✓	✓	✓			✓				✓			
CLK5p	✓	✓	✓				✓				✓		
CLK6p	✓			✓	✓			✓				✓	
CLK7p	✓			✓	✓				✓				✓
CLK4n		✓				✓				✓			
CLK5n			✓				✓				✓		
CLK6n				✓				✓				✓	
CLK7n					✓				✓				✓
Drivers from internal logic													
GCLKDRV0		✓											
GCLKDRV1			✓										
GCLKDRV2				✓									

The bus-hold circuitry also pulls undriven pins away from the input threshold voltage where noise can cause unintended high-frequency switching. You can select this feature individually for each I/O pin. The bus-hold output drives no higher than V_{CCIO} to prevent overdriving signals. If the bus-hold feature is enabled, the programmable pull-up option cannot be used. Disable the bus-hold feature when the I/O pin has been configured for differential signals.

The bus-hold circuitry uses a resistor with a nominal resistance (R_{BH}) of approximately 7 kΩ to weakly pull the signal level to the last-driven state. See the *DC & Switching Characteristics* chapter in the *Stratix II Device Handbook, Volume 1*, for the specific sustaining current driven through this resistor and overdrive current used to identify the next-driven input level. This information is provided for each V_{CCIO} voltage level.

The bus-hold circuitry is active only after configuration. When going into user mode, the bus-hold circuit captures the value on the pin present at the end of configuration.

Programmable Pull-Up Resistor

Each Stratix II device I/O pin provides an optional programmable pull-up resistor during user mode. If you enable this feature for an I/O pin, the pull-up resistor (typically 25 kΩ) weakly holds the output to the V_{CCIO} level of the output pin's bank.

Programmable pull-up resistors are only supported on user I/O pins, and are not supported on dedicated configuration pins, JTAG pins or dedicated clock pins.

Advanced I/O Standard Support

Stratix II device IOEs support the following I/O standards:

- 3.3-V LVTTL/LVCMOS
- 2.5-V LVTTL/LVCMOS
- 1.8-V LVTTL/LVCMOS
- 1.5-V LVCMOS
- 3.3-V PCI
- 3.3-V PCI-X mode 1
- LVDS
- LVPECL (on input and output clocks only)
- HyperTransport technology
- Differential 1.5-V HSTL Class I and II
- Differential 1.8-V HSTL Class I and II
- Differential SSTL-18 Class I and II
- Differential SSTL-2 Class I and II

- 1.5-V HSTL Class I and II
- 1.8-V HSTL Class I and II
- 1.2-V HSTL
- SSTL-2 Class I and II
- SSTL-18 Class I and II

Table 2–16 describes the I/O standards supported by Stratix II devices.

Table 2–16. Stratix II Supported I/O Standards (Part 1 of 2)

I/O Standard	Type	Input Reference Voltage (V_{REF}) (V)	Output Supply Voltage (V_{CCIO}) (V)	Board Termination Voltage (V_{TT}) (V)
LVTTL	Single-ended	-	3.3	-
LVCMOS	Single-ended	-	3.3	-
2.5 V	Single-ended	-	2.5	-
1.8 V	Single-ended	-	1.8	-
1.5-V LVCMOS	Single-ended	-	1.5	-
3.3-V PCI	Single-ended	-	3.3	-
3.3-V PCI-X mode 1	Single-ended	-	3.3	-
LVDS	Differential	-	2.5 *(3)*	-
LVPECL *(1)*	Differential	-	3.3	-
HyperTransport technology	Differential	-	2.5	-
Differential 1.5-V HSTL Class I and II *(2)*	Differential	0.75	1.5	0.75
Differential 1.8-V HSTL Class I and II *(2)*	Differential	0.90	1.8	0.90
Differential SSTL-18 Class I and II *(2)*	Differential	0.90	1.8	0.90
Differential SSTL-2 Class I and II *(2)*	Differential	1.25	2.5	1.25
1.2-V HSTL*(4)*	Voltage-referenced	0.6	1.2	0.6
1.5-V HSTL Class I and II	Voltage-referenced	0.75	1.5	0.75
1.8-V HSTL Class I and II	Voltage-referenced	0.9	1.8	0.9
SSTL-18 Class I and II	Voltage-referenced	0.90	1.8	0.90

4. Hot Socketing & Power-On Reset

SII51004-3.2

Stratix® II devices offer hot socketing, which is also known as hot plug-in or hot swap, and power sequencing support without the use of any external devices. You can insert or remove a Stratix II board in a system during system operation without causing undesirable effects to the running system bus or the board that was inserted into the system.

The hot socketing feature also removes some of the difficulty when you use Stratix II devices on printed circuit boards (PCBs) that also contain a mixture of 5.0-, 3.3-, 2.5-, 1.8-, 1.5- and 1.2-V devices. With the Stratix II hot socketing feature, you no longer need to ensure a proper power-up sequence for each device on the board.

The Stratix II hot socketing feature provides:

- Board or device insertion and removal without external components or board manipulation
- Support for any power-up sequence
- Non-intrusive I/O buffers to system buses during hot insertion

This chapter also discusses the power-on reset (POR) circuitry in Stratix II devices. The POR circuitry keeps the devices in the reset state until the V_{CC} is within operating range.

Stratix II Hot-Socketing Specifications

Stratix II devices offer hot socketing capability with all three features listed above without any external components or special design requirements. The hot socketing feature in Stratix II devices allows:

- The device can be driven before power-up without any damage to the device itself.
- I/O pins remain tri-stated during power-up. The device does not drive out before or during power-up, thereby affecting other buses in operation.
- Signal pins do not drive the V_{CCIO}, V_{CCPD}, or V_{CCINT} power supplies. External input signals to I/O pins of the device do not internally power the V_{CCIO} or V_{CCINT} power supplies of the device via internal paths within the device.

Devices Can Be Driven Before Power-Up

You can drive signals into the I/O pins, dedicated input pins and dedicated clock pins of Stratix II devices before or during power-up or power-down without damaging the device. Stratix II devices support any power-up or power-down sequence (V_{CCIO}, V_{CCINT}, and V_{CCPD}) in order to simplify system level design.

I/O Pins Remain Tri-Stated During Power-Up

A device that does not support hot-socketing may interrupt system operation or cause contention by driving out before or during power-up. In a hot socketing situation, Stratix II device's output buffers are turned off during system power-up or power-down. Stratix II device also does not drive out until the device is configured and has attained proper operating conditions.

Signal Pins Do Not Drive the V_{CCIO}, V_{CCINT} or V_{CCPD} Power Supplies

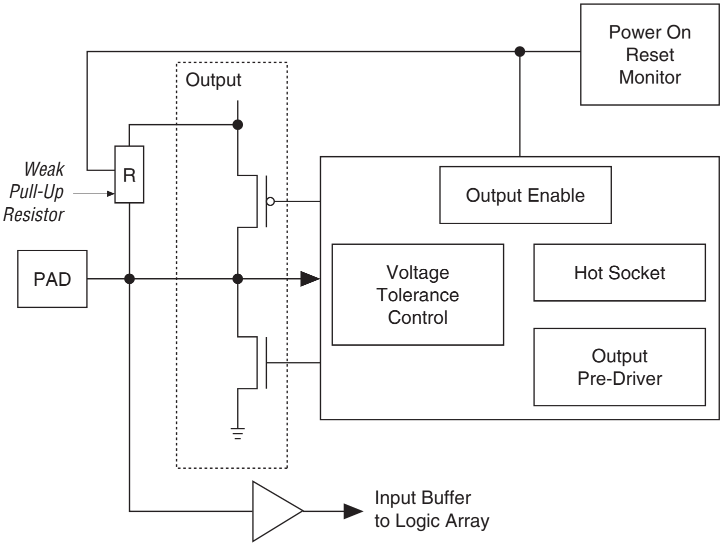
Devices that do not support hot-socketing can short power supplies together when powered-up through the device signal pins. This irregular power-up can damage both the driving and driven devices and can disrupt card power-up.

Stratix II devices do not have a current path from I/O pins, dedicated input pins, or dedicated clock pins to the V_{CCIO}, V_{CCINT}, or V_{CCPD} pins before or during power-up. A Stratix II device may be inserted into (or removed from) a powered-up system board without damaging or interfering with system-board operation. When hot-socketing, Stratix II devices may have a minimal effect on the signal integrity of the backplane.

☞ You can power up or power down the V_{CCIO}, V_{CCINT}, and V_{CCPD} pins in any sequence. The power supply ramp rates can range from 100 µs to 100 ms. All V_{CC} supplies must power down within 100 ms of each other to prevent I/O pins from driving out. During hot socketing, the I/O pin capacitance is less than 15 pF and the clock pin capacitance is less than 20 pF. Stratix II devices meet the following hot socketing specification.

- The hot socketing DC specification is: $|I_{IOPIN}| < 300\ \mu A$.
- The hot socketing AC specification is: $|I_{IOPIN}| < 8$ mA for 10 ns or less.

Figure 4–1. Hot Socketing Circuit Block Diagram for Stratix II Devices



The POR circuit monitors V_{CCINT} voltage level and keeps I/O pins tri-stated until the device is in user mode. The weak pull-up resistor (R) from the I/O pin to V_{CCIO} is present to keep the I/O pins from floating. The 3.3-V tolerance control circuit permits the I/O pins to be driven by 3.3 V before V_{CCIO} and/or V_{CCINT} and/or V_{CCPD} are powered, and it prevents the I/O pins from driving out when the device is not in user mode. The hot socket circuit prevents I/O pins from internally powering V_{CCIO}, V_{CCINT}, and V_{CCPD} when driven by external signals before the device is powered.

Figure 4–2 shows a transistor level cross section of the Stratix II device I/O buffers. This design ensures that the output buffers do not drive when V_{CCIO} is powered before V_{CCINT} or if the I/O pad voltage is higher than V_{CCIO}. This also applies for sudden voltage spikes during hot insertion. There is no current path from signal I/O pins to V_{CCINT} or V_{CCIO} or V_{CCPD} during hot insertion. The V_{PAD} leakage current charges the 3.3-V tolerant circuit capacitance.

Table 5–4. Stratix II Device DC Operating Conditions (Part 2 of 2) Note (1)

Symbol	Parameter	Conditions		Minimum	Typical	Maximum	Unit
I_{CCI00}	V_{CCIO} supply current (standby)	V_I = ground, no load, no toggling inputs T_J = 25° C	EP2S15		4.0	(3)	mA
			EP2S30		4.0	(3)	mA
			EP2S60		4.0	(3)	mA
			EP2S90		4.0	(3)	mA
			EP2S130		4.0	(3)	mA
			EP2S180		4.0	(3)	mA
R_{CONF} (4)	Value of I/O pin pull-up resistor before and during configuration	Vi = 0; V_{CCIO} = 3.3 V		10	25	50	kΩ
		Vi = 0; V_{CCIO} = 2.5 V		15	35	70	kΩ
		Vi = 0; V_{CCIO} = 1.8 V		30	50	100	kΩ
		Vi = 0; V_{CCIO} = 1.5 V		40	75	150	kΩ
		Vi = 0; V_{CCIO} = 1.2 V		50	90	170	kΩ
	Recommended value of I/O pin external pull-down resistor before and during configuration				1	2	kΩ

Notes to Table 5–4:

(1) Typical values are for T_A = 25°C, V_{CCINT} = 1.2 V, and V_{CCIO} = 1.5 V, 1.8 V, 2.5 V, and 3.3 V.

(2) This value is specified for normal device operation. The value may vary during power-up. This applies for all V_{CCIO} settings (3.3, 2.5, 1.8, and 1.5 V).

(3) Maximum values depend on the actual T_J and design utilization. See the Excel-based PowerPlay Early Power Estimator (available at **www.altera.com**) or the Quartus II PowerPlay Power Analyzer feature for maximum values. See the section "Power Consumption" on page 5–20 for more information.

(4) Pin pull-up resistance values are lower if an external source drives the pin higher than V_{CCIO}.

I/O Standard Specifications

Tables 5–5 through 5–32 show the Stratix II device family I/O standard specifications.

Table 5–5. LVTTL Specifications (Part 1 of 2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} (1)	Output supply voltage		3.135	3.465	V
V_{IH}	High-level input voltage		1.7	4.0	V
V_{IL}	Low-level input voltage		–0.3	0.8	V
V_{OH}	High-level output voltage	I_{OH} = –4 mA (2)	2.4		V

Table 5–41. M4K Block Internal Timing Microparameters (Part 2 of 2) *Note (1)*

Symbol	**Parameter**	**-3 Speed Grade** *(2)*		**-3 Speed Grade** *(3)*		**-4 Speed Grade**		**-5 Speed Grade**		**Unit**
		Min *(4)*	**Max**	**Min** *(4)*	**Max**	**Min** *(5)*	**Max**	**Min** *(4)*	**Max**	
$t_{M4KDATAASU}$	A port data setup time before clock	22		23		25 25		29		ps
$t_{M4KDATAAH}$	A port data hold time after clock	203		213		233 233		272		ps
$t_{M4KADDRASU}$	A port address setup time before clock	22		23		25 25		29		ps
$t_{M4KADDRAH}$	A port address hold time after clock	203		213		233 233		272		ps
$t_{M4KDATABSU}$	B port data setup time before clock	22		23		25 25		29		ps
$t_{M4KDATABH}$	B port data hold time after clock	203		213		233 233		272		ps
$t_{M4KRADDRBSU}$	B port address setup time before clock	22		23		25 25		29		ps
$t_{M4KRADDRBH}$	B port address hold time after clock	203		213		233 233		272		ps
$t_{M4KDATACO1}$	Clock-to-output delay when using output registers	334	524	334	549	319 334	601	334	701	ps
$t_{M4KDATACO2}$ *(6)*	Clock-to-output delay without output registers	1,616	2,453	1,616	2,574	1,540 1,616	2,820	1,616	3,286	ps
$t_{M4KCLKH}$	Minimum clock high time	1,250		1,312		1,437 1,437		1,675		ps
$t_{M4KCLKL}$	Minimum clock low time	1,250		1,312		1,437 1,437		1,675		ps
t_{M4KCLR}	Minimum clear pulse width	144		151		165 165		192		ps

Notes to Table 5–41:

(1) F_{MAX} of M4K Block obtained using the Quartus II software does not necessarily equal to 1/TM4KRC.

(2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.

(3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.

(4) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.

(5) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

(6) Numbers apply to unpacked memory modes, true dual-port memory modes, and simple dual-port memory modes that use locally routed or non-identical sources for the A and B port registers.

Table 5–53. EP2S60 Column Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.658	1.739	2.920	3.350	3.899	ns
t_{COUT}	1.501	1.574	2.678	3.072	3.575	ns
t_{PLLCIN}	0.06	0.057	0.278	0.304	0.355	ns
$t_{PLLCOUT}$	-0.097	-0.108	0.036	0.026	0.031	ns

Table 5–54. EP2S60 Row Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.463	1.532	2.591	2.972	3.453	ns
t_{COUT}	1.468	1.537	2.587	2.968	3.448	ns
t_{PLLCIN}	-0.153	-0.167	-0.079	-0.099	-0.128	ns
$t_{PLLCOUT}$	-0.148	-0.162	-0.083	-0.103	-0.133	ns

Table 5–55. EP2S60 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.439	1.508	2.562	2.940	3.421	ns
t_{COUT}	1.444	1.513	2.558	2.936	3.416	ns
t_{PLLCIN}	-0.161	-0.174	-0.083	-0.107	-0.126	ns
$t_{PLLCOUT}$	-0.156	-0.169	-0.087	-0.111	-0.131	ns

Therefore, the DCD percentage for the 267 MHz SSTL-2 Class II DDIO row output clock on a –3 device ranges from 48.4% to 51.6%.

Table 5–83. Maximum DCD for DDIO Output on Row I/O Pins Without PLL in the Clock Path for -4 & -5 Devices Notes (1), (2)

Row DDIO Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in the Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	LVDS/ HyperTransport Technology	
	3.3/2.5 V	1.8/1.5 V	2.5 V	1.8/1.5 V	3.3 V	
3.3-V LVTTL	440	495	170	160	105	ps
3.3-V LVCMOS	390	450	120	110	75	ps
2.5 V	375	430	105	95	90	ps
1.8 V	325	385	90	100	135	ps
1.5-V LVCMOS	430	490	160	155	100	ps
SSTL-2 Class I	355	410	85	75	85	ps
SSTL-2 Class II	350	405	80	70	90	ps
SSTL-18 Class I	335	390	65	65	105	ps
1.8-V HSTL Class I	330	385	60	70	110	ps
1.5-V HSTL Class I	330	390	60	70	105	ps
LVDS/ HyperTransport technology	180	180	180	180	180	ps

Notes to Table 5–83:

(1) Table 5–83 assumes the input clock has zero DCD.

(2) The DCD specification is based on a no logic array noise condition.

Table 5–84. Maximum DCD for DDIO Output on Column I/O Pins Without PLL in the Clock Path for -3 Devices (Part 1 of 2) Notes (1), (2)

DDIO Column Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in the Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	1.2-V HSTL	
	3.3/2.5 V	1.8/1.5 V	2.5 V	1.8/1.5 V	1.2 V	
3.3-V LVTTL	260	380	145	145	145	ps
3.3-V LVCMOS	210	330	100	100	100	ps
2.5 V	195	315	85	85	85	ps

High-Speed I/O Specifications

Table 5–88 provides high-speed timing specifications definitions.

Table 5–88. High-Speed Timing Specifications & Definitions

High-Speed Timing Specifications	Definitions
t_C	High-speed receiver/transmitter input and output clock period.
f_{HSCLK}	High-speed receiver/transmitter input and output clock frequency.
J	Deserialization factor (width of parallel data bus).
W	PLL multiplication factor.
t_{RISE}	Low-to-high transmission time.
t_{FALL}	High-to-low transmission time.
Timing unit interval (TUI)	The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = 1/(Receiver Input Clock Frequency × Multiplication Factor) = t_C/w).
f_{HSDR}	Maximum/minimum LVDS data transfer rate (f_{HSDR} = 1/TUI), non-DPA.
$f_{HSDRDPA}$	Maximum/minimum LVDS data transfer rate ($f_{HSDRDPA}$ = 1/TUI), DPA.
Channel-to-channel skew (TCCS)	The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew. The clock is included in the TCCS measurement.
Sampling window (SW)	The period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window.
Input jitter	Peak-to-peak input jitter on high-speed PLLs.
Output jitter	Peak-to-peak output jitter on high-speed PLLs.
t_{DUTY}	Duty cycle on high-speed transmitter output clock.
t_{LOCK}	Lock time for high-speed transmitter and receiver PLLs.

Table 5–89 shows the high-speed I/O timing specifications for -3 speed grade Stratix II devices.

Table 5–89. High-Speed I/O Specifications for -3 Speed Grade (Part 1 of 2) *Notes (1), (2)*

Symbol	Conditions	-3 Speed Grade			Unit
		Min	Typ	Max	
f_{HSCLK} (clock frequency) $f_{HSCLK} = f_{HSDR}$ / W	W = 2 to 32 (LVDS, HyperTransport technology) *(3)*	16		520	MHz
	W = 1 (SERDES bypass, LVDS only)	16		500	MHz
	W = 1 (SERDES used, LVDS only)	150		717	MHz

PLL Timing Specifications

Tables 5–92 and 5–93 describe the Stratix II PLL specifications when operating in both the commercial junction temperature range (0 to 85 °C) and the industrial junction temperature range (–40 to 100 °C).

Table 5–92. Enhanced PLL Specifications (Part 1 of 2)

Name	Description	Min	Typ	Max	Unit
f_{IN}	Input clock frequency	2		500	MHz
f_{INPFD}	Input frequency to the PFD	2		420	MHz
f_{INDUTY}	Input clock duty cycle	40		60	%
$f_{EINDUTY}$	External feedback input clock duty cycle	40		60	%
$t_{INJITTER}$	Input or external feedback clock input jitter tolerance in terms of period jitter. Bandwidth ≤ 0.85 MHz		0.5		ns (p-p)
	Input or external feedback clock input jitter tolerance in terms of period jitter. Bandwidth > 0.85 MHz		1.0		ns (p-p)
$t_{OUTJITTER}$	Dedicated clock output period jitter			250 ps for ≥ 100 MHz `outclk` 25 mUI for < 100 MHz `outclk`	ps or mUI (p-p)
t_{FCOMP}	External feedback compensation time			10	ns
f_{OUT}	Output frequency for internal global or regional clock	1.5 *(2)*		550.0	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output (when set to 50%).	45	50	55	%
$f_{SCANCLK}$	Scanclk frequency			100	MHz
$t_{CONFIGPLL}$	Time required to reconfigure scan chains for enhanced PLLs		$174/f_{SCANCLK}$		ns
f_{OUT_EXT}	PLL external clock output frequency	1.5 *(2)*		550.0 *(1)*	MHz

Table 5–103. Document Revision History (Part 2 of 3)

Date and Document Version	Changes Made	Summary of Changes
August, 2006, v4.2	Updated Table 5–73, Table 5–75, Table 5–77, Table 5–78, Table 5–79, Table 5–81, Table 5–85, and Table 5–87.	—
April 2006, v4.1	● Updated Table 5–3. ● Updated Table 5–11. ● Updated Figures 5–8 and 5–9. ● Added parallel on-chip termination information to “On-Chip Termination Specifications” section. ● Updated Tables 5–28, 5–30,5–31, and 5–34. ● Updated Table 5–78, Tables 5–81 through 5–90, and Tables 5–92, 5–93, and 5–98. ● Updated “PLL Timing Specifications” section. ● Updated “External Memory Interface Specifications” section. ● Added Tables 5–95 and 5–101. ● Updated “JTAG Timing Specifications” section, including Figure 5–10 and Table 5–102.	● Changed 0.2 MHz to 2 MHz in Table 5–93. ● Added new spec for half period jitter (Table 5–101). ● Added support for PLL clock switchover for industrial temperature range. ● Changed f_{INPFD} (min) spec from 4 MHz to 2 MHz in Table 5–92. ● Fixed typo in $t_{OUTJITTER}$ specification in Table 5–92. ● Updated V_{DIF} AC & DC max specifications in Table 5–28. ● Updated minimum values for t_{JCH}, t_{JCL}, and t_{JPSU} in Table 5–102. ● Update maximum values for t_{JPCO}, t_{JPZX}, and t_{JPXZ} in Table 5–102.
December 2005, v4.0	● Updated “External Memory Interface Specifications” section. ● Updated timing numbers throughout chapter.	—
July 2005, v3.1	● Updated HyperTransport technology information in Table 5–13. ● Updated “Timing Model” section. ● Updated “PLL Timing Specifications” section. ● Updated “External Memory Interface Specifications” section.	—
May 2005, v3.0	● Updated tables throughout chapter. ● Updated “Power Consumption” section. ● Added various tables. ● Replaced “Maximum Input & Output Clock Rate” section with “Maximum Input & Output Clock Toggle Rate” section. ● Added “Duty Cycle Distortion” section. ● Added “External Memory Interface Specifications” section.	—
March 2005, v2.2	Updated tables in “Internal Timing Parameters” section.	—
January 2005, v2.1	Updated input rise and fall time.	—